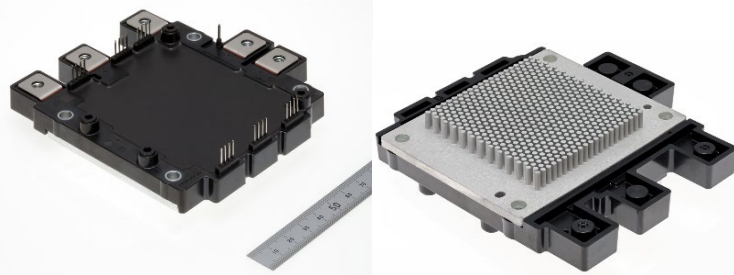


<IGBT Modules>

CT700CJ1A060-A

**HIGH POWER SWITCHING USE
INSULATED TYPE**



Collector current I_c	700 A
Collector-emitter voltage V_{CES}	650 V

- High-Reliability DLB structure*^{Note}
- Direct cooling package with cooling fin
- Compact, light-weight, high-power-density module
- 6-Elements package (6-in-1, insulated type)
- Low internal impedance package
- Low-loss CSTBT™ chip technology*^{Note}
- Built-in on-chip temperature sensor
- Built-in on-chip current sensor for SC protection
- Compliant with RoHS directive 2011/65/EU
- High strength material(Al)

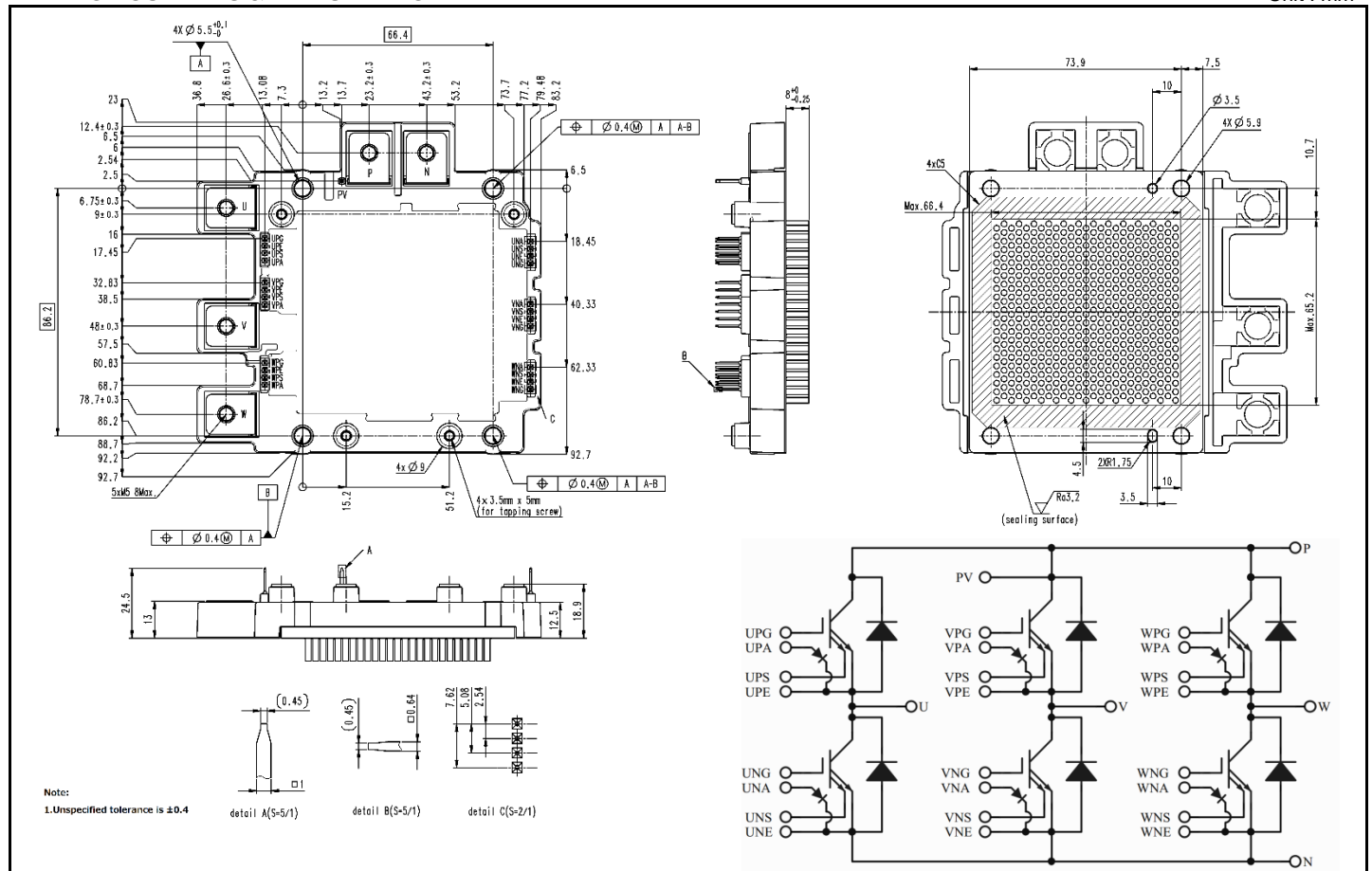
*Note DLB: Direct-Lead-Bonding (Wire-bond-Less power contacts); CSTBT™: Carrier Stored Trench Gate Bipolar Transistor

APPLICATION

EV/HEV and High Reliability Inverter

PACKAGE OUTLINES & CIRCUIT DIAGRAM

Unit : mm



CT700CJ1A060-A

HIGH POWER SWITCHING USE
INSULATED TYPE

ABSOLUTE MAXIMUM RATINGS (T_{vj} = 25°C, unless otherwise noted)

Symbol	Item	Conditions	Ratings	Unit
V _{CES}	Collector-emitter voltage	-40°C ≤ T _{vj} < 25°C, V _{GE} = 0V	650	V
		25°C ≤ T _{vj} ≤ 150 °C, V _{GE} = 0V	714	V
		25°C ≤ T _{vj} ≤ 150 °C, V _{GE} = 0V (Non-repetition of abnormal operation)	750	V
V _{GES}	Gate-emitter voltage	V _{GE} = 0V	±20	V
I _C	Collector current	T _W = 25°C	700	A
I _{CRM}	Peak collector current	T _W = 25°C, Repetitive, pulse ^(Note 1)	1400	A
I _E	Emitter current	T _W = 25°C	700	A
I _{ERM}	Peak emitter current	T _W = 25°C, Repetitive, pulse ^(Note 1)	1400	A
P _{tot}	Maximum collector dissipation	T _W = 25°C, T _{vj} = 175°C	773	W
T _{vj}	Junction temperature	Repetition	-40 ~ +150	°C
		Non-repetition, Accumulated time 100hour	+150 ~ +175	°C
T _{stg}	Storage temperature	—	-40 ~ +125	°C
V _{isol}	Isolation voltage	Main terminals to base plate, AC 1 minute, 60Hz	2500	V _{rms}

MECHANICAL RATINGS

Symbol	Item	Conditions	Limits			Unit	
			Min.	Typ.	Max.		
—	Tightening torque strength	Main terminal screw : M5	Torque coefficient =0.32	2.8	3.2	6.0	Nm
		Mounting screw : M5		2.8	3.2	6.0	Nm
—	Weight	Typical value	—	340	—	g	

ELECTRICAL CHARACTERISTICS (T_{vj} = 25°C, unless otherwise noted)

Symbol	Item	Conditions	Limits			Unit		
			Min.	Typ.	Max.			
I _{CES}	Collector cut-off current	V _{CE} = V _{CES} , V _{GE} = 0V	—	—	1	mA		
V _{GE(th)}	Gate-emitter threshold voltage	I _C = 70mA, V _{CE} = 10V	5.5	6.5	7.5	V		
I _{GES}	Gate leakage current	V _{GE} = V _{GES}	—	—	15	μA		
V _{CEsat}	Collector-emitter saturation voltage	I _C = 700A V _{GE} = 15V	T _{vj} = 25°C	Main terminal	—	1.60	1.89	V
				Chip	—	1.25	—	V
		T _{vj} = 125°C	Main terminal	—	1.70	2.01	V	
			Chip	—	1.25	—	V	
V _{EC}	Emitter-collector voltage	I _E = 700A, V _{GE} = 0V T _{vj} = 25°C	Main terminal	—	1.60	1.89	V	
			Chip	—	1.45	—	V	
C _{ies}	Input capacitance	V _{CE} = 10V	—	57	—	nF		
C _{oes}	Output capacitance	V _{GE} = 0V	—	7.7	—	nF		
C _{res}	Reverse transfer capacitance	T _{vj} = 25°C	—	1.0	—	nF		
V _F	On-chip temperature-sense diode voltage	I _F = 200μA	2.65	2.75	2.85	V		
		I _F = 200μA, T _{vj} = 125°C	1.98	2.08	2.18	V		
t _{d(on)}	Turn-on delay time	V _{CC} = 350V, I _C = I _E = 700A V _{GE} = 15V, T _{vj} = 125°C R _{G(on)} = 3.6Ω (dI _C /dt ≒ 4.5kA/μs) R _{G(off)} = 4.7Ω (dI _C /dt ≒ 4.0kA/μs) L _s = 15nH Inductive load switching operation. Note) see switching measurement circuit on page6	—	0.25	—	μs		
t _r	Turn-on rise time		—	0.16	—	μs		
E _{on}	Turn-on loss		—	34.4	—	mJ/p		
t _{d(off)}	Turn-off delay time		—	1.00	—	μs		
t _f	Turn-off fall time		—	0.22	—	μs		
E _{off}	Turn-off loss		—	56.8	—	mJ/p		
t _{rr}	Reverse-recovery time		—	0.26	—	μs		
Q _{rr}	Reverse-recovery charge		—	50.3	—	μC		
E _{rr}	Reverse-recovery loss		—	15.9	—	mJ/p		

THERMAL RESISTANCES

Symbol	Item	Conditions	Limits			Unit	
			Min.	Typ.	Max.		
R _{th(j-w)Q}	Junction-water thermal resistance	IGBT part (1/6 module)	50% LLC : Flow rate: 10L/min	—	0.164	0.194	K/W
R _{th(j-w)D}		FWD part (1/6 module)		—	0.180	0.212	K/W

Note1 : Pulse width and repetition rate should be such that the device junction temperature (T_{vj}) dose not exceed maximum ratings.

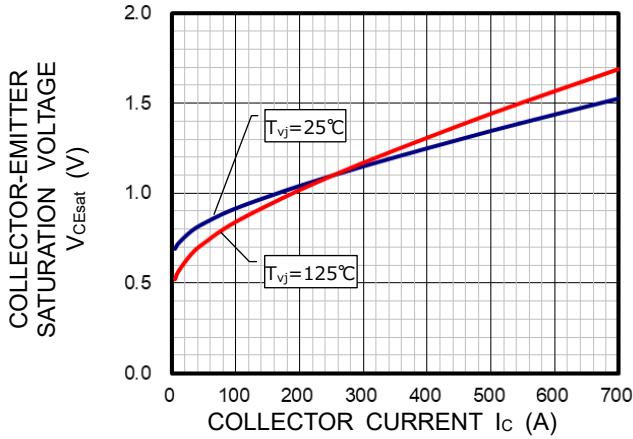
CT700CJ1A060-A

HIGH POWER SWITCHING USE
INSULATED TYPE

PERFORMANCE CURVES

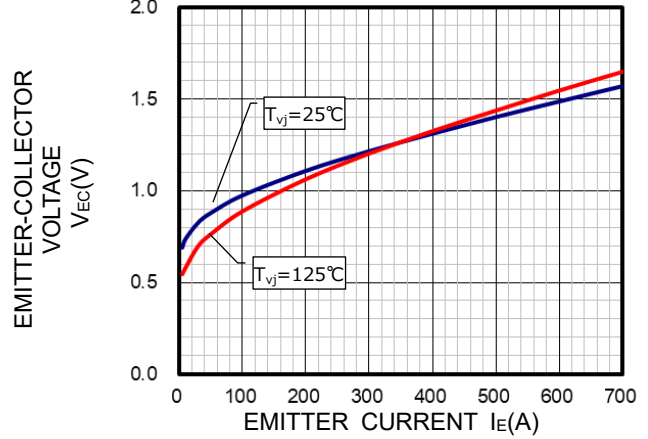
COLLECTOR-EMITTER SATURATION CHARACTERISTICS
(Representative Example:Main terminal)

$V_{GE}=15V$



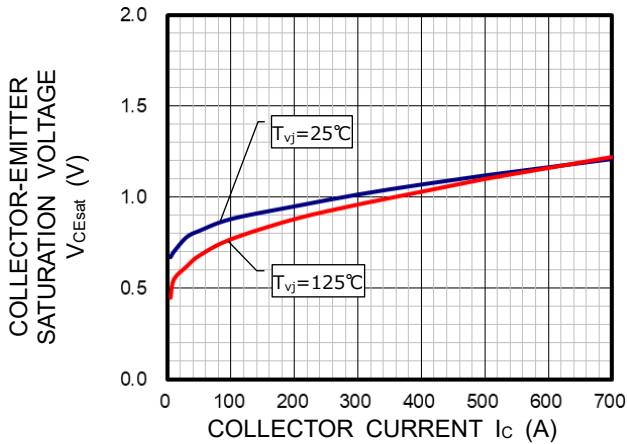
FREE-WHEEL DIODE FORWARD CHARACTERISTICS
(Representative Example:Main terminal)

$V_{GE}=0V$



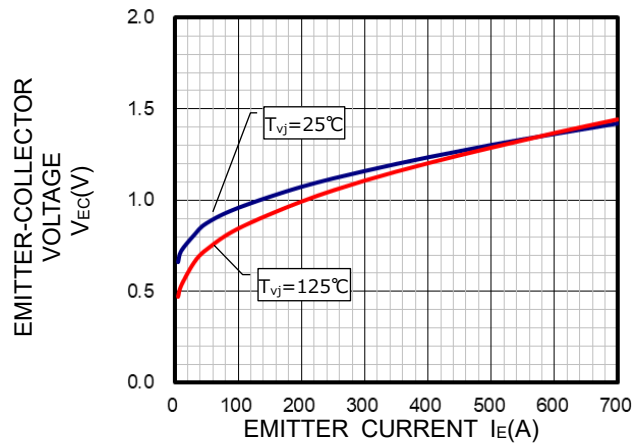
COLLECTOR-EMITTER SATURATION CHARACTERISTICS
(Representative Example:Chip)

$V_{GE}=15V$



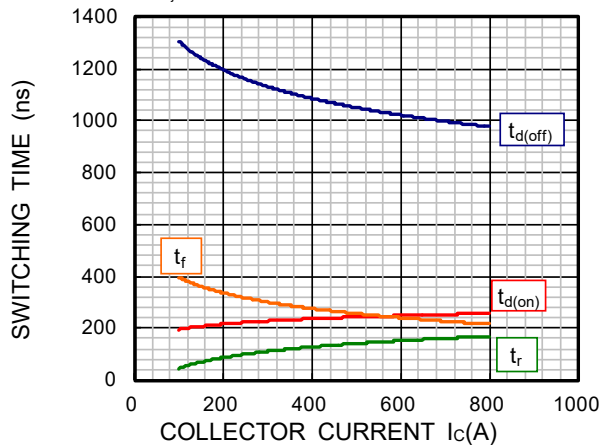
FREE-WHEEL DIODE FORWARD CHARACTERISTICS
(Representative Example:Chip)

$V_{GE}=0V$



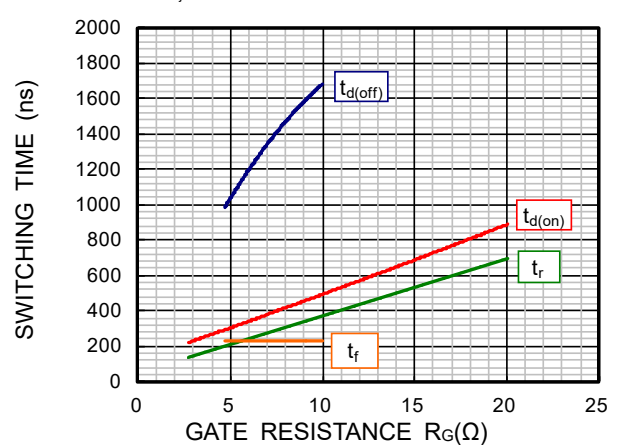
SWITCHING CHARACTERISTICS
(Representative Example)

$V_{CC}=350V, V_{GE}=15V, R_{G(on)}=3.6\Omega, R_{G(off)}=4.7\Omega, T_{vj}=125^\circ C, L_s=15nH$, Inductive load



SWITCHING CHARACTERISTICS
(Representative Example)

$V_{CC}=350V, I_C=700A, V_{GE}=15V, T_{vj}=125^\circ C, L_s=15nH$, Inductive load

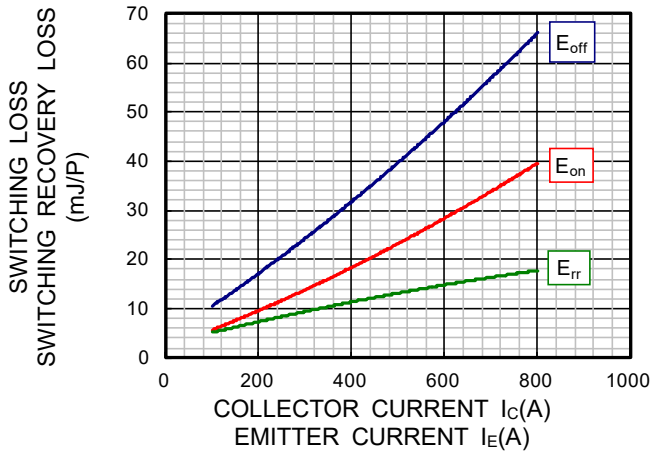


CT700CJ1A060-A

HIGH POWER SWITCHING USE
INSULATED TYPE

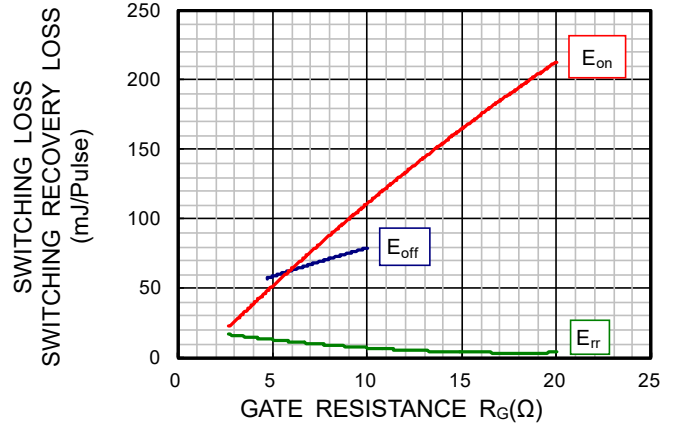
SWITCHING CHARACTERISTICS (Representative Example)

$V_{CC}=350V$, $V_{GE}=15V$, $R_{G(on)}=3.6\Omega$, $R_{G(off)}=4.7\Omega$,
 $T_{vj}=125^{\circ}C$, $L_s=15nH$, Inductive load



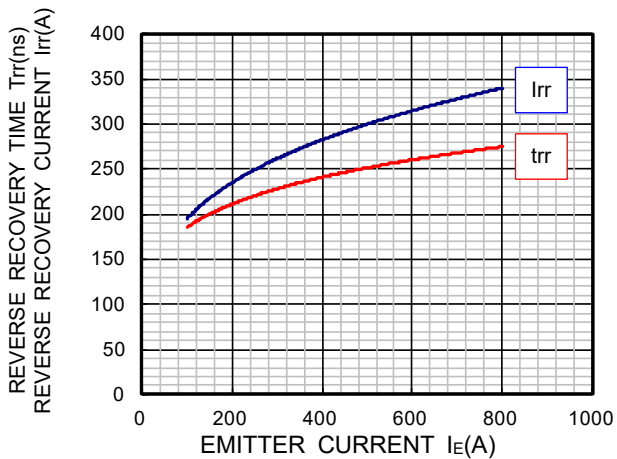
SWITCHING CHARACTERISTICS (Representative Example)

$V_{CC}=350V$, $I_C=I_E=700A$, $V_{GE}=15V$,
 $T_{vj}=125^{\circ}C$, $L_s=15nH$, Inductive load



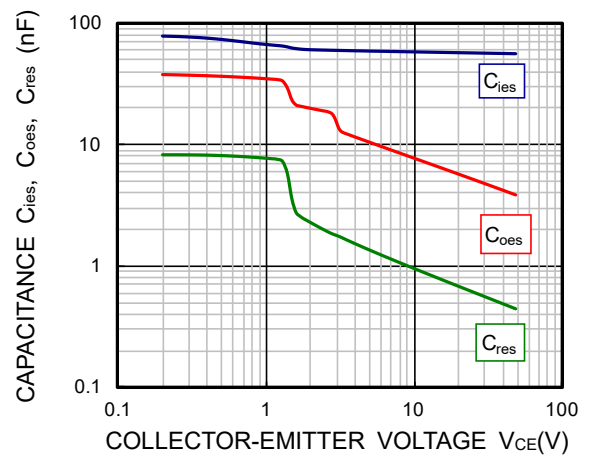
FREE-WHEEL DIODE REVERSE RECOVERY CHARACTERISTICS (Representative Example)

$V_{CC}=350V$, $V_{GE}=15V$, $R_{G(on)}=3.6\Omega$,
 $T_{vj}=125^{\circ}C$, $L_s=15nH$, Inductive load



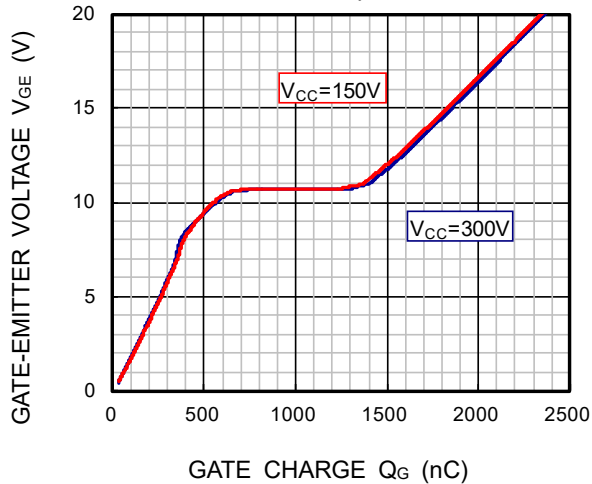
CAPACITANCE-vs.-VCE CHARACTERISTICS (Representative Example)

$T_{vj}=25^{\circ}C$



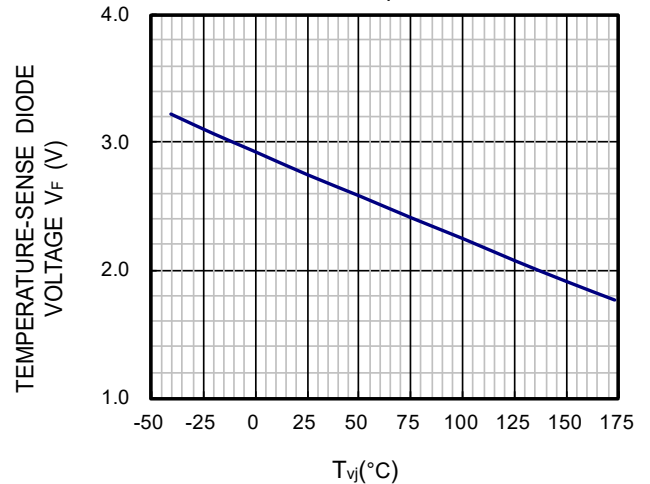
GATE CHARGE CHARACTERISTICS (Representative Example)

$I_C=700A$, $T_{vj}=25^{\circ}C$



ON-CHIP TEMPERATURE-SENSE DIODE CHARACTERISTICS (Representative Example)

$I_F=200\mu A$

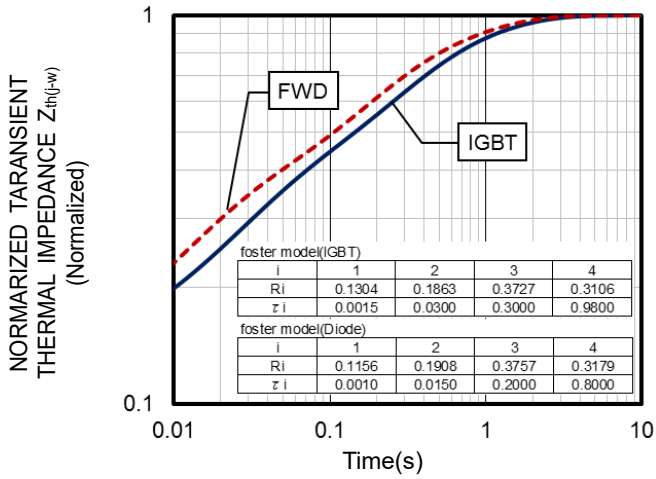


CT700CJ1A060-A

HIGH POWER SWITCHING USE
INSULATED TYPE

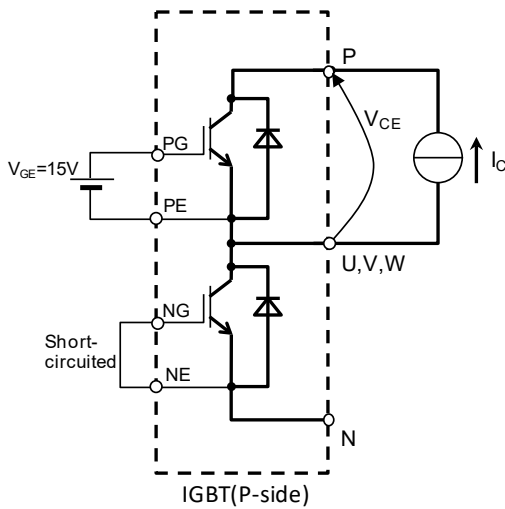
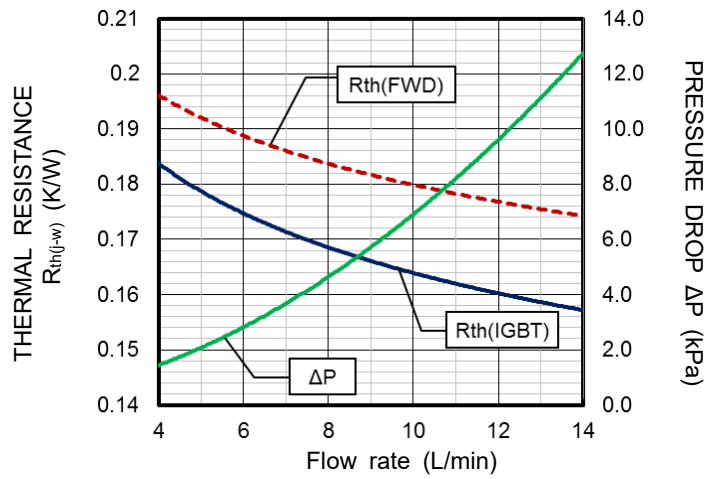
TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (Representative Example)

IGBT part: Per unit base= $R_{th(j-w)Q}=0.164K/W$
FWD part: Per unit base= $R_{th(j-w)D}=0.180K/W$

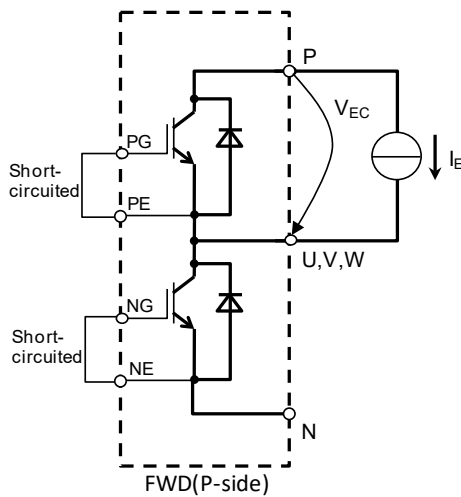
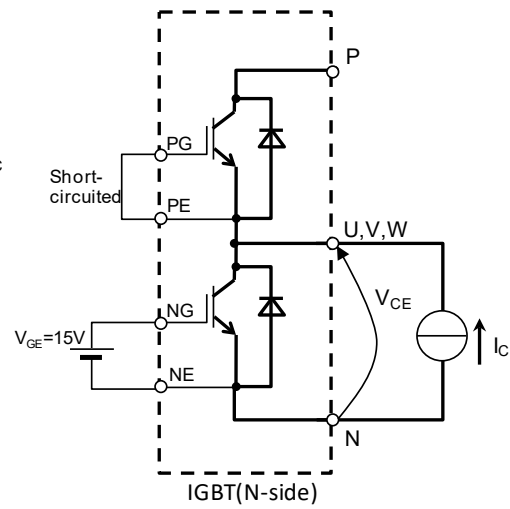


THERMAL RESISTANCE, PRESSURE DROP CHARACTERISTICS (Representative Example)

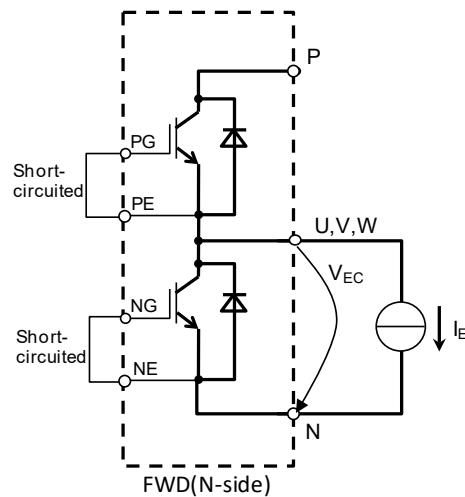
$T_w=60^{\circ}C$, 50%LLC
cooling jacket(J1WJB)



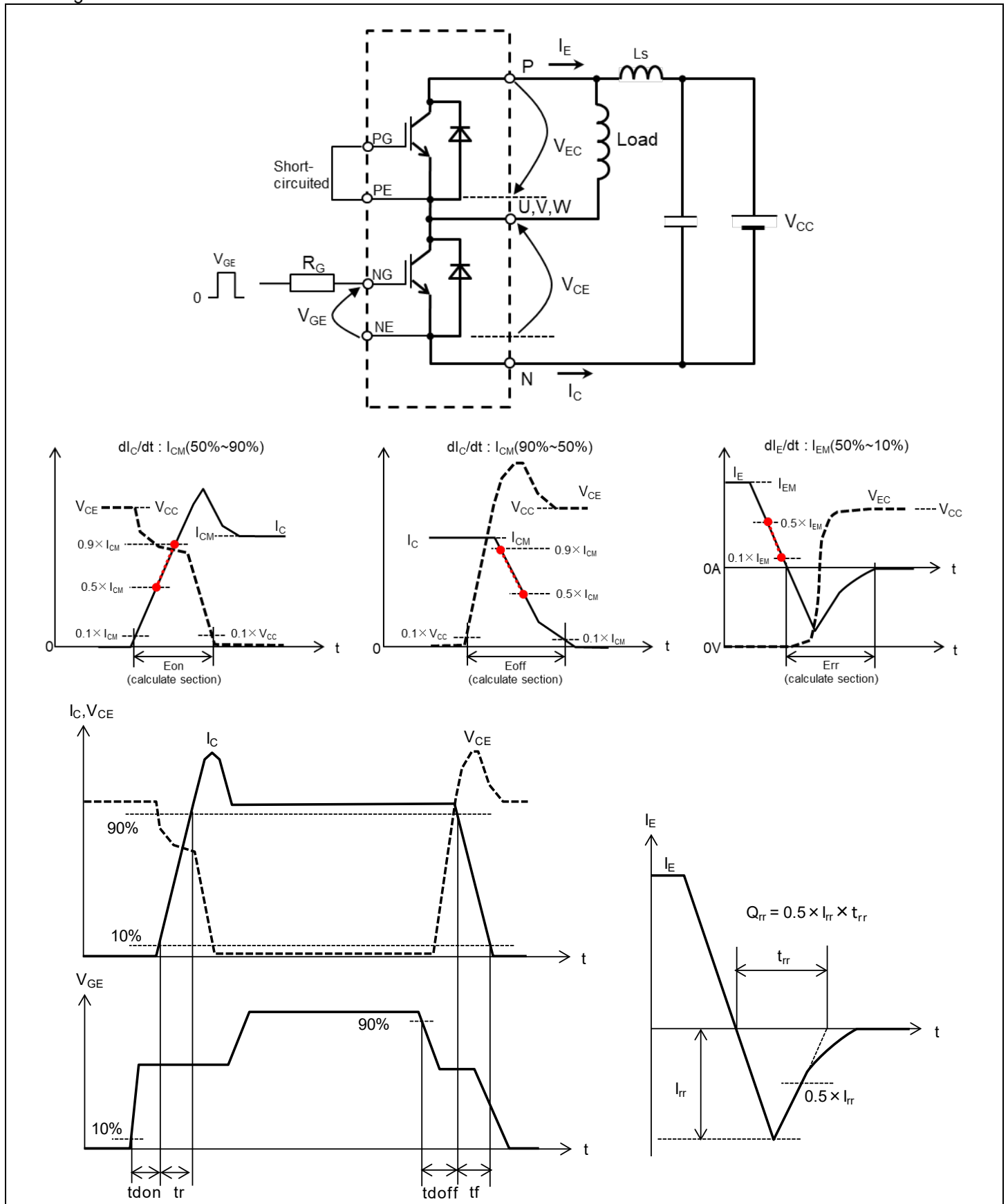
$V_{CE(sat)}$ Measurement circuit (Main terminal)



V_{EC} Measurement circuit (Main terminal)




Switching measurement circuit



Correct and Safety Use of Power Module

Unsuitable operation (such as electrical, mechanical stress and so on) may lead to damage of power modules.

Please pay attention to the following descriptions and use Mitsubishi Electric's IGBT modules according to the guidance.

 CAUTION	
During Transit	<p>(1) Keep shipping cartons right side up. If stress is applied by either placing a carton upside down or by leaning a box against something, terminals can be bent and/or resin packages can be damaged.</p> <p>(2) Tossing or dropping of a carton may damage devices inside.</p> <p>(3) If a device gets wet with water, malfunctioning and failure may result. Special care should be taken during rain or snow to prevent the devices from getting wet.</p>
Storage	<p>The temperature and humidity of the storage place should be 5~35°C and 45~75% respectively. The performance and reliability of devices may be jeopardized if devices are stored in an environment far above or below the range indicated above.</p>
Prolonged Storage	<p>When storing devices more than one year, dehumidifying measures should be provided for the storage place. When using devices after a long period of storage, make sure to check the exterior of the devices is free from scratches, dirt, rust, and so on.</p>
Operating Environment	<p>Devices should not be exposed to water, organic solvents, corrosive gases, explosive gases, fine particles, or corrosive agents, since any of those can lead to a serious accident.</p>
Flame Resistance	<p>Although the epoxy resin is in conformity with UL 94-V0 standards, it should be noted that those are not non-flammable.</p>
Anti-electrostatic Measures	<p>Following precautions should be taken for MOS-gated devices to prevent static buildup which could damage the devices.</p> <p>(1) Precautions against the device rupture caused by static electricity Static electricity of human bodies and cartons and/or excessive voltage applied across the gate to emitter may damage and rupture devices. Sense-emitter and temperature-sensor are also vulnerable to excessive voltage. The basis of anti-electrostatic is suppression of build-up and quick dissipation of the charged electricity.</p> <ul style="list-style-type: none">① Containers that are susceptible to static electricity should not be used for transit or for storage.② Signal terminals to emitter should be always shorted with a carbon cloth or the like until right before a module is used. Never touch the signal terminals with bare hands.③ Always ground the equipment and your body during installation (after removing a carbon cloth or the like. It is advisable to cover the workstation and its surrounding floor with conductive mats and ground them.④ It should be noted that devices may get damaged by the static electricity charged to a printed circuit board if the signal terminals to emitter of the circuit board are open.⑤ Use soldering irons with grounded tips. <p>(2) Precautions when the signal terminals to emitter are open</p> <ul style="list-style-type: none">① Voltage should not be applied across the collector to emitter when the signal terminals to emitter are open.② The signal terminals to emitter should be shorted before removing a device from a unit.

Important Notice

The information contained in this datasheet shall in no event be regarded as a guarantee of conditions or characteristics. This product has to be used within its specified maximum ratings, and is subject to customer's compliance with any applicable legal requirement, norms and standards.

Except as otherwise explicitly approved by Mitsubishi Electric Corporation in a written document signed by authorized representatives of Mitsubishi Electric Corporation, our products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.

In usage of power semiconductor, there is always the possibility that trouble may occur with them by the reliability lifetime such as Power Cycle, Thermal Cycle or others, or when used under special circumstances (e.g. condensation, high humidity, dusty, salty, highlands, environment with lots of organic matter / corrosive gas / explosive gas, or situations which terminals of semiconductor products receive strong mechanical stress). Therefore, please pay sufficient attention to such circumstances. Further, depending on the technical requirements, our semiconductor products may contain environmental regulation substances, etc. If there is necessity of detailed confirmation, please contact our nearest sales branch or distributor.

The contents or data contained in this datasheet are exclusively intended for technically trained staff. Customer's technical departments should take responsibility to evaluate the suitability of Mitsubishi Electric Corporation product for the intended application and the completeness of the product data with respect to such application. In the customer's research and development, please evaluate it not only with a single semiconductor product but also in the entire system, and judge whether it's applicable. As required, pay close attention to the safety design by installing appropriate fuse or circuit breaker between a power supply and semiconductor products to prevent secondary damage. Please also pay attention to the application note and the related technical information.

Keep safety first in your circuit designs!

Mitsubishi Electric Corporation puts the maximum effort into making semiconductor products better and more reliable, but there is always the possibility that trouble may occur with them. Trouble with semiconductors may lead to personal injury, fire or property damage. Remember to give due consideration to safety when making your circuit designs, with appropriate measures such as (i) placement of substitutive, auxiliary circuits, (ii) use of non-flammable material or (iii) prevention against any malfunction or mishap.

Notes regarding these materials

- These materials are intended as a reference to assist our customers in the selection of the Mitsubishi Electric Semiconductor product best suited to the customer's application; they do not convey any license under any intellectual property rights, or any other rights, belonging to Mitsubishi Electric Corporation or a third party.
- Mitsubishi Electric Corporation assumes no responsibility for any damage, or infringement of any third-party's rights, originating in the use of any product data, diagrams, charts, programs, algorithms, or circuit application examples contained in these materials.
- All information contained in these materials, including product data, diagrams, charts, programs and algorithms represents information on products at the time of publication of these materials, and are subject to change by Mitsubishi Electric Corporation without notice due to product improvements or other reasons. It is therefore recommended that customers contact Mitsubishi Electric Corporation or an authorized Mitsubishi Electric Semiconductor product distributor for the latest product information before purchasing a product listed herein.
The information described here may contain technical inaccuracies or typographical errors. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability, or other loss rising from these inaccuracies or errors.
Please also pay attention to information published by Mitsubishi Electric Corporation by various means, including the Mitsubishi Electric Semiconductor home page (<http://www.MitsubishiElectric.com/semiconductor/>).
- When using any or all of the information contained in these materials, including product data, diagrams, charts, programs, and algorithms, please be sure to evaluate all information as a total system before making a final decision on the applicability of the information and products. Mitsubishi Electric Corporation assumes no responsibility for any damage, liability or other loss resulting from the information contained herein.
- Mitsubishi Electric Corporation semiconductors are not designed or manufactured for use in a device or system that is used under circumstances in which human life is potentially at stake. Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Electric Semiconductor product distributor when considering the use of a product contained herein for any specific purposes, such as apparatus or systems for transportation, vehicular, medical, aerospace, nuclear, or undersea repeater use.
- The prior written approval of Mitsubishi Electric Corporation is necessary to reprint or reproduce in whole or in part these materials.
- If these products or technologies are subject to the Japanese export control restrictions, they must be exported under a license from the Japanese government and cannot be imported into a country other than the approved destination.
Any diversion or re-export contrary to the export control laws and regulations of Japan and/or the country of destination is prohibited.
- Please contact Mitsubishi Electric Corporation or an authorized Mitsubishi Electric Semiconductor product distributor for further details on these materials or the products contained therein.

CSTBT are registered trademarks of Mitsubishi Electric.